



Product Change Notification - KSRA-09NUVS538

Date:

22 Aug 2018

Product Category:

Others; Ethernet PHYs

Affected CPNs:**Notification subject:**

CCB 2881 Initial Notice: Qualification of ASE as a new assembly site for selected Micrel products available in 32L VQFN package using palladium coated copper with gold flash (CuPdAu) bond wire

Notification text:**PCN Status:**

Initial notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of ASE as a new assembly site for selected Micrel products available in 32L VQFN package using palladium coated copper with gold flash (CuPdAu) bond wire

Pre Change:

Assembled at TICIP using gold (Au) bond wire

Post Change:

Assembled at ASE using palladium coated copper with gold flash (CuPdAu) bond wire

Pre and Post Change Summary:

| | Pre Change | | Post Change |
|----------------------------------|-------------------------------|----|----------------|
| Assembly Site | Taiwan IC Packing Corp (TICP) | | ASE Inc. (ASE) |
| Wire material | Au | Ag | CuPdAu |
| Die attach material | EN-4900 | | EN-4900 |
| Molding compound material | G631 | | G631 |
| Lead frame material | C194 | | C194 |

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve productivity by qualifying ASE as new assembly site

Change Implementation Status:

In Progress

Estimated Qualification Completion Date:

October 2018

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may



receive pre and post change parts.

Time Table Summary:

| | August 2018 | | | | | | October 2018 | | | | |
|--------------------------|-------------|----|----|----|----|--|--------------|----|----|----|----|
| Workweek | 31 | 32 | 33 | 34 | 35 | | 36 | 37 | 38 | 39 | 40 |
| Initial PCN Issue Date | | | | X | | | | | | | |
| Qual Report Availability | | | | | | | X | | | | |
| Final PCN Issue Date | | | | | | | X | | | | |

Method to Identify Change:

Traceability code

Qualification Plan:

Please open the attachments included with this PCN labeled as PCN_#_Qual Plan.

Revision History:

August 22, 2018: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

[PCN_KSRA-09NUVS538_Qual_Plan.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to change your product/process change notification (PCN) profile please log on to our website at <http://www.microchip.com/PCN> sign into myMICROCHIP to open the myMICROCHIP home page, then select a profile option from the left navigation bar.

To opt out of future offer or information emails (other than product change notification emails), click here to go to [microchipDIRECT](#) and login, then click on the "My account" link, click on "Update profile" and un-check the box that states "Future offers or information about Microchip's products or services."

Affected Catalog Part Numbers (CPN)

KSZ8041NL
KSZ8041NLI
KSZ8041NLI-TR
KSZ8041NLJ-TR
KSZ8041NL-TR
KSZ8041RNL
KSZ8041RNLI
KSZ8041RNLI-TR
KSZ8041RNL-TR
SPNY801052-TR
SPNY801165
SPNY801165-TR
SPNY801167
SPNY801167-TR
SPNZ801034-TR
SPNZ801050-TR
SPNZ801052-TR
SPNZ801059
SPNZ801059-TR
SPNZ801111-TR
SPNZ801165
SPNZ801165-TR
SPNZ801166
SPNZ801166-TR
SPNZ801167
SPNZ801167-TR



MICROCHIP

QUALIFICATION PLAN SUMMARY

PCN#: KSRA-09NUVS538

**Date:
August 7, 2018**

**Qualification of ASE as a new assembly site for selected
Micrel products available in 32L VQFN package using
palladium coated copper with gold flash (CuPdAu) bond wire**

Purpose: Qualification of ASE as a new assembly site for selected Micrel products available in 32L VQFN package using palladium coated copper with gold flash (CuPdAu) bond wire

CCB No.: 2881

| | | |
|-------------------|---------------------------|---------------------|
| Misc. | Assembly site | ASE |
| | BD Number | AAH@A226260030-0 |
| | MP Code (MPC) | TKDA1SPFAB02 |
| | Part Number (CPN) | KSZ8041NL |
| Lead-Frame | Paddle size | 3.70 mm x 3.70 mm |
| | Material | C194 |
| | Surface | Double Ring plating |
| | Treatment | Non-Rough |
| | Process | Etch |
| | Lead-lock | No |
| | Part Number | A22626-0 |
| | Lead Plating | Sn |
| Bond Wire | Material | CuPdAu |
| Die Attach | Part Number | EN4900 |
| | Conductive | Yes |
| MC | Part Number | G631H |
| PKG | PKG Type | VQFN |
| | Pin/Ball Count | 32 LD |
| | PKG width/size | 5.5x0.9 mm |
| | PKG LD Finish | Sn |
| | PKG MSL | 2 |
| Die | Die Thickness | 9 mils |
| | Die Size | 1.511 mm x 1.327 mm |
| | Fab Process (site) | 180nm_Dongbu |

| Test Name | Conditions | Sample Size | Min. Qty of Spares per Lot (should be properly) | Qty of Lots | Total Units | Fail Accept Qty | Est. Dur. Days | Special Instructions |
|--|--|---|---|-------------|-------------|--------------------------------|----------------|--|
| Standard Pb-free Solderability | JESD22B-102E; Perform 8 hour steam aging for Matte tin finish and 1 hour steam aging | 22 | 5 | 1 | 27 | > 95% lead coverage | 5 | Standard Pb-free solderability is the requirement. SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes. |
| Wire Bond Pull - WBP | Mil. Std. 883-2011 | 5 | 0 | 3 | 24 | 0 fails after TC | 5 | 30 bonds from a minimum of 5 devices. |
| Wire Bond Shear - WBS | CDF-AEC-Q100-001 | 5 | 0 | 3 | 24 | | 5 | 30 bonds from a minimum of 5 devices. |
| Bond Line Thickness (BLT) robustness assessment | | 5 | 1 | 3 | 15 | >0.5 mils | | |
| Wire Sweep | | 5 | 0 | 3 | 15 | 0 | | Required for any reduction in wire bond thickness. |
| Physical Dimensions | Measure per JESD22 B100 and B108 | 10 | 0 | 3 | 30 | 0 | 5 | - |
| Lead Integrity | JESD22 B105 | 5 | 0 | 1 | 5 | 0 (No lead breakage or cracks) | 5 | 10 leads from each of 5 parts. Not required for SMD, only required for through-hole. |
| External Visual | Mil. Std. 883-2009/2010 | All devices prior to submission for qualification testing | 0 | 3 | ALL | 0 | 5 | |
| Preconditioning - Required for surface mount devices | +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020D for package type; Electrical test pre and post stress at +25°C. MSL- 2 @ 260°C | 231 | 15 | 3 | 738 | 0 | 15 | Spares should be properly identified. 77 parts from each lot to be used for HAST, Autoclave, Temp Cycle test. |
| HAST | +130°C/85% RH for 96 hours, 192 hours Electrical test pre and post stress at +25°C | 77 | 5 | 3 | 246 | 0 | 10 | |
| Unbiased HAST | +130°C/85% RH for 96 hrs., Electrical test pre and post stress at +25°C. | 77 | 5 | 3 | 246 | 0 | 10 | Spares should be properly identified. Use the parts which have gone through Pre-conditioning. |
| Temp Cycle | -65°C to +150°C for 500 cycles. Electrical test pre and post stress at hot temp; 3 gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress. | 77 | 5 | 3 | 246 | 0 | 15 | Spares should be properly identified. Use the parts which have gone through Pre-conditioning. |



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